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	PAT. NO.		Title
1	11,269,170	T	Separate microscopy system and adjusting method thereof
2	11,209,371	T	Optical detecting device and calibrating method
3	11,169,178	T	Locking mechanism for a press head and electronic device testing apparatus comprising the same
4	11,156,669	T	Battery testing device and method thereof
5	11,143,640	T	Rotating buffer station for a chip
6	11,080,860	T	Image inspection method
7	11,073,852	T	Electronic load apparatus
8	11,061,067	T	Apparatus and method for a high temperature test and a low temperature test and configured to maintain an electronic component under test near a test temperature
9	10,989,660	T	Automatic fluorescence detection system
10	10,965,096	T	Fixture assembly for testing surface emitting laser diodes and testing apparatus having the same
11	10,948,518	T	Test apparatus for testing electronic device
12	10,910,627	T	Battery formation system and probe supporting structure thereof
13	10,903,618	T	Fixture assembly for testing edge-emitting laser diodes and testing apparatus having the same
14	10,890,624	T	Testing fixture, testing system for cell temperature probe and method for testing cell temperature probe
15	10,879,097	T	Modular pressing device capable of generating stage downward forces and electronic device testing apparatus comprising the same
16	10,845,386	T	Probe pin alignment apparatus
17	10,825,588	T	Voltage dividing resistor
18	10,811,720	T	Battery cell tray
19	10,802,070	T	Testing device and testing method with spike protection
20	10,718,635	T	Contact detection circuit of four-terminal measurement device
21	10,712,366	T	Electrical probe
22	10,673,104	T	Method for testing semi-finished battery cell

23 10,670,627 T Electrical probe structure
24 10,665,906 T Battery cell formation device and probe supporting structure thereof
25 10,527,671 T Absorption testing apparatus
26 10,520,528 T Dew resistant module for test socket and electronic component testing device having the same
27 10,508,969 T Method and device for testing air tightness
28 10,488,459 T Device for pressing electronic component with different downward forces
29 10,481,209 T Method for checking a wire connection
30 10,436,636 T Optical measuring device
31 10,436,580 T Surface measurement system
32 10,411,646 T Inspection method and inspection system of solar cell
33 10,309,986 T Temperature-controlled module for electronic devices and testing apparatus provided with the same
34 10,291,116 T Output control method for a digital controller of a source measure unit
35 10,254,310 T Electrical probe with a probe head and contacting pins
36 10,254,308 T Electronic device testing apparatus with locking mechanism for pressing header and socket plate
37 10,215,812 T Clamp-type probe device
38 10,034,410 T Support apparatus
39 9,983,259 T Dual loop type temperature control module and electronic device testing apparatus provided with the same
40 9,954,255 T Measurement fixture for a battery cell
41 9,841,737 T Automatic test system and method
42 9,841,487 T Calibration board for calibrating signal delays of test channels in an automatic test equipment and timing calibration method thereof
43 9,823,295 T Battery simulator
44 9,706,098 T Inspection system and method for obtaining an adjusted light intensity image
45 9,678,158 T Apparatus for testing a package-on-package semiconductor device
46 9,658,283 T Radiator module system for automatic test equipment
47 9,647,650 T Clock generating device
48 9,638,740 T Test system with rotational test arms for testing semiconductor components
49 9,568,245 T Heating furnace
50 9,519,024 T Apparatus for testing package-on-package semiconductor device and method for testing the same

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